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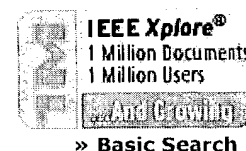
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L2	(spin\$4 or spun or counterspin\$4 or counterspun).ti,ab.	345001	L2
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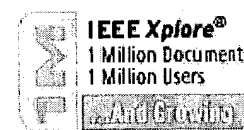
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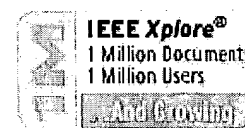
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And

canard In: All Fields

And

counterspin In: All Fields

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And

canard In: All Fields

And

spin In: All Fields

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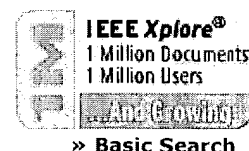
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Mickle, M.C.; Zhu, J.J.;

American Control Conference, 2001. Proceedings of the 2001 , Volume: 5 , 25-27
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And

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And

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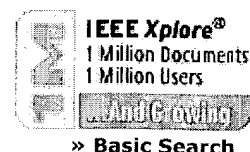
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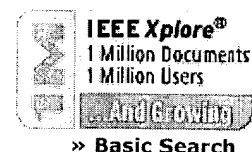
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And

canard In: All Fields

And

spin In: All Fields

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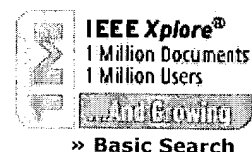
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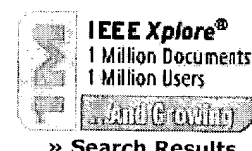
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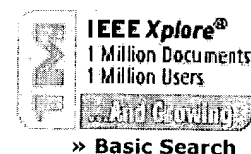
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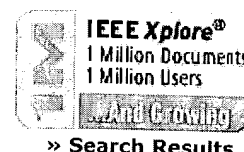
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